Abstracts

A Quick Accurate Method to Measure the Dielectric Constant of Microwave Integrated-Circuit Substrates (Short Papers)

J.Q. Howell. "A Quick Accurate Method to Measure the Dielectric Constant of Microwave Integrated-Circuit Substrates (Short Papers)." 1973 Transactions on Microwave Theory and Techniques 21.3 (Mar. 1973 [T-MTT]): 142-144.

A technique is described that makes possible the accurate measurement of the dielectric constant of microwave integrated-circuit substrates. The substrate is metallized on all sides, hence forming a tiny resonant cavity, and the resonant frequencies are determined either from transmission or reflection. The dielectric constant is then calculated to an accuracy of better than 1 percent.

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